

Search Notes

Application/Control No.

10/815,162

Examiner

Hiep Nguyen

Applicant(s)/Patent under
Reexamination

WU, STEPHEN

Art Unit

2816

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST See attachment	09.08.05	Nh